

Fig. 1

FIG. 2 is a schematic diagram of a system for measuring the rate of change of a physical property of a material. The system includes a sample 30, a sensor 40, a data acquisition system 50, and a computer 60. The sample 30 is placed in a container 20, and the sensor 40 is positioned to measure the property of the sample. The data acquisition system 50 is connected to the sensor 40 and the computer 60, which is used to process the data and determine the rate of change of the property.

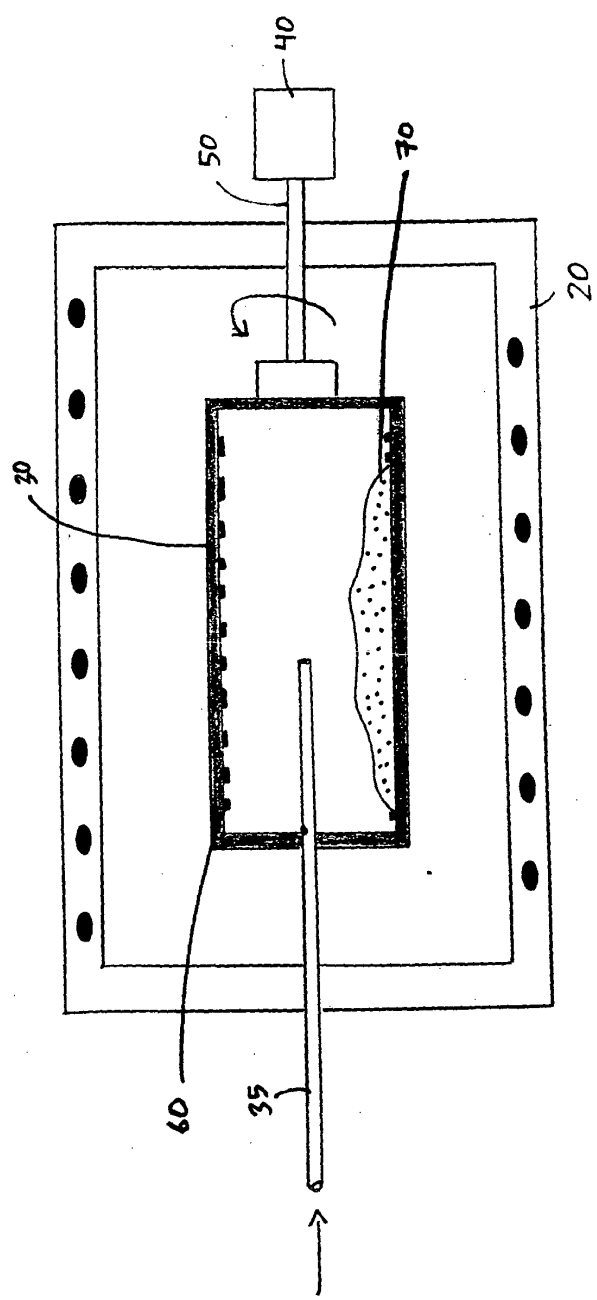


FIG. 2

FIG 3A

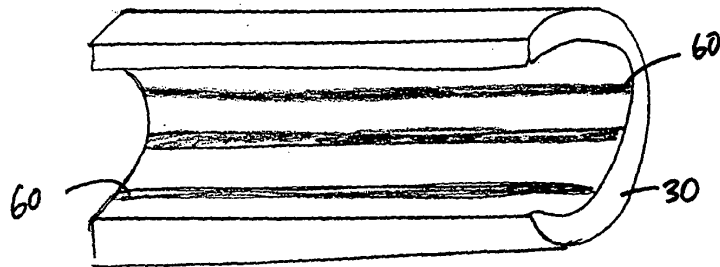
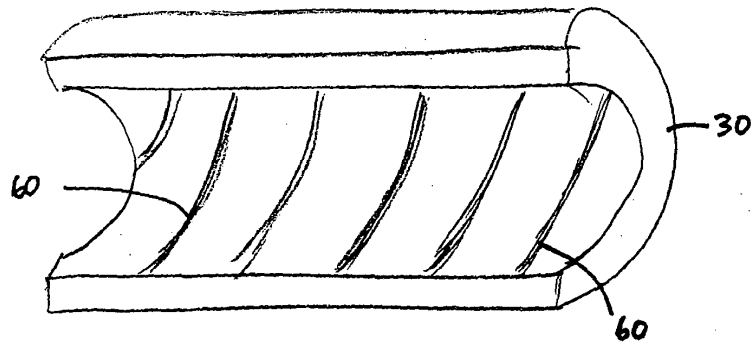


FIG 3B



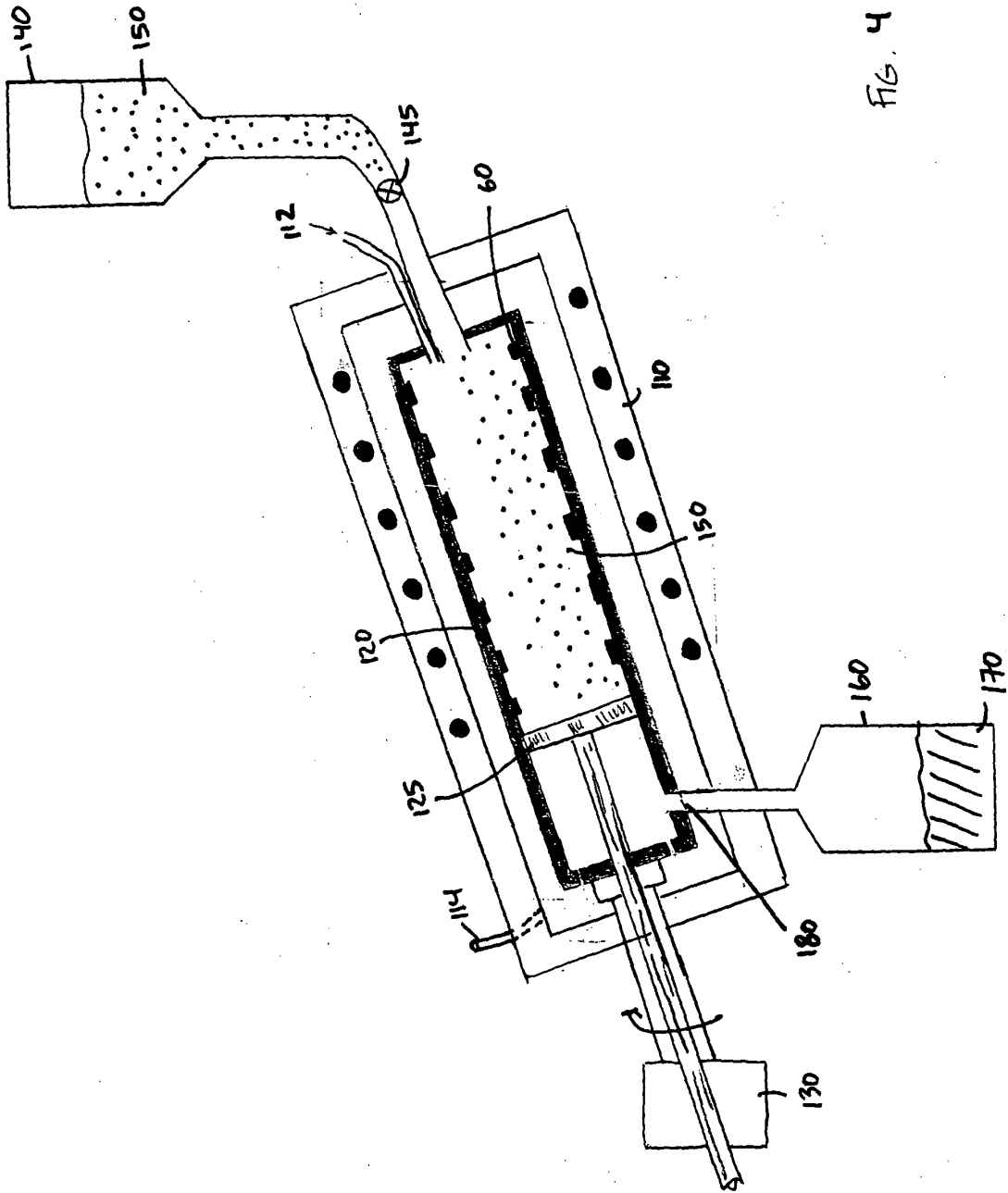


FIG. 4

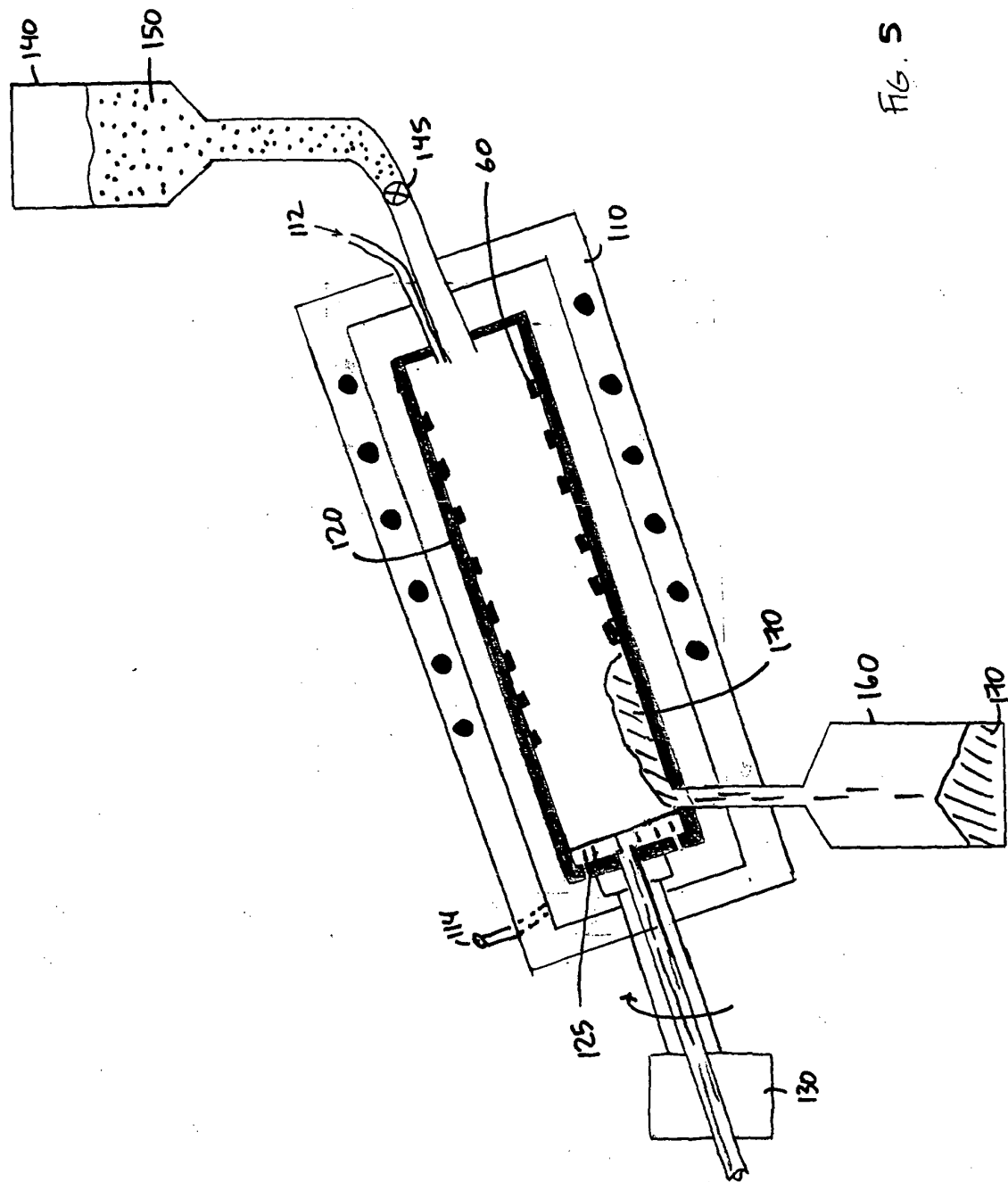


FIG. 5

300

300

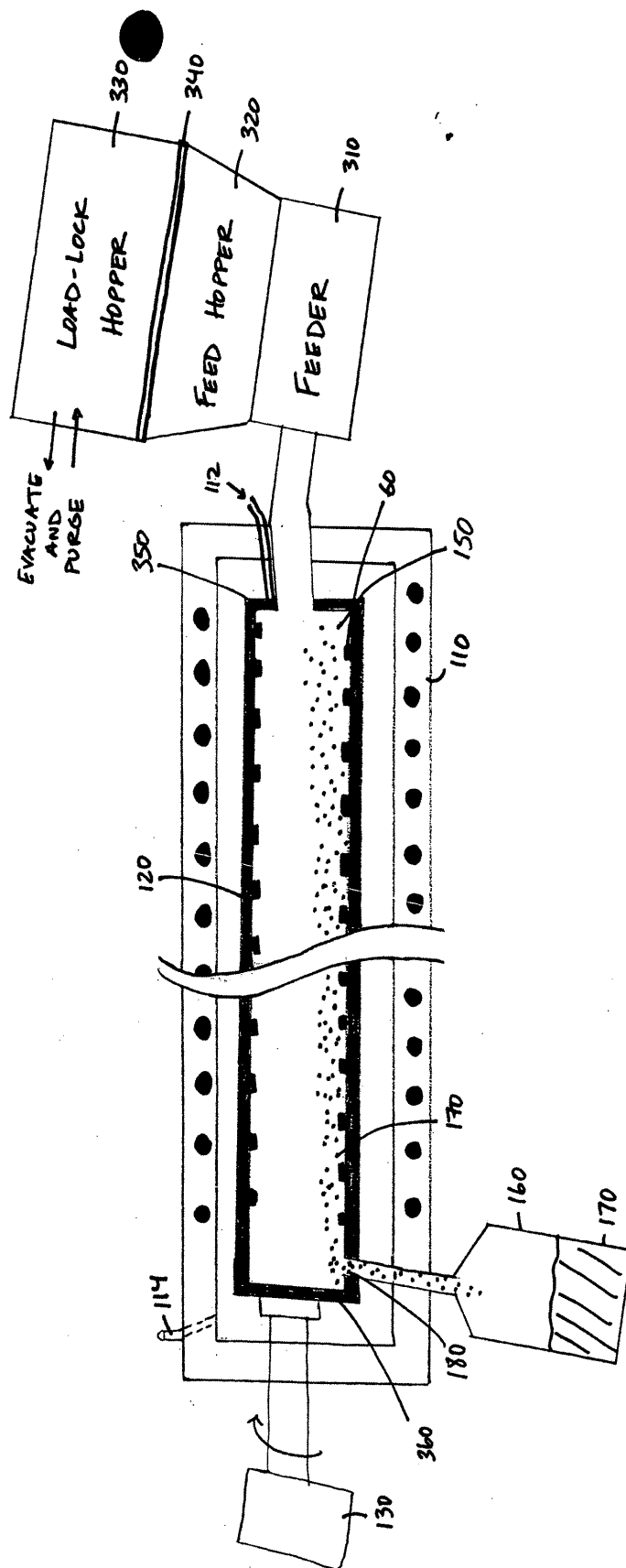


FIG. 6

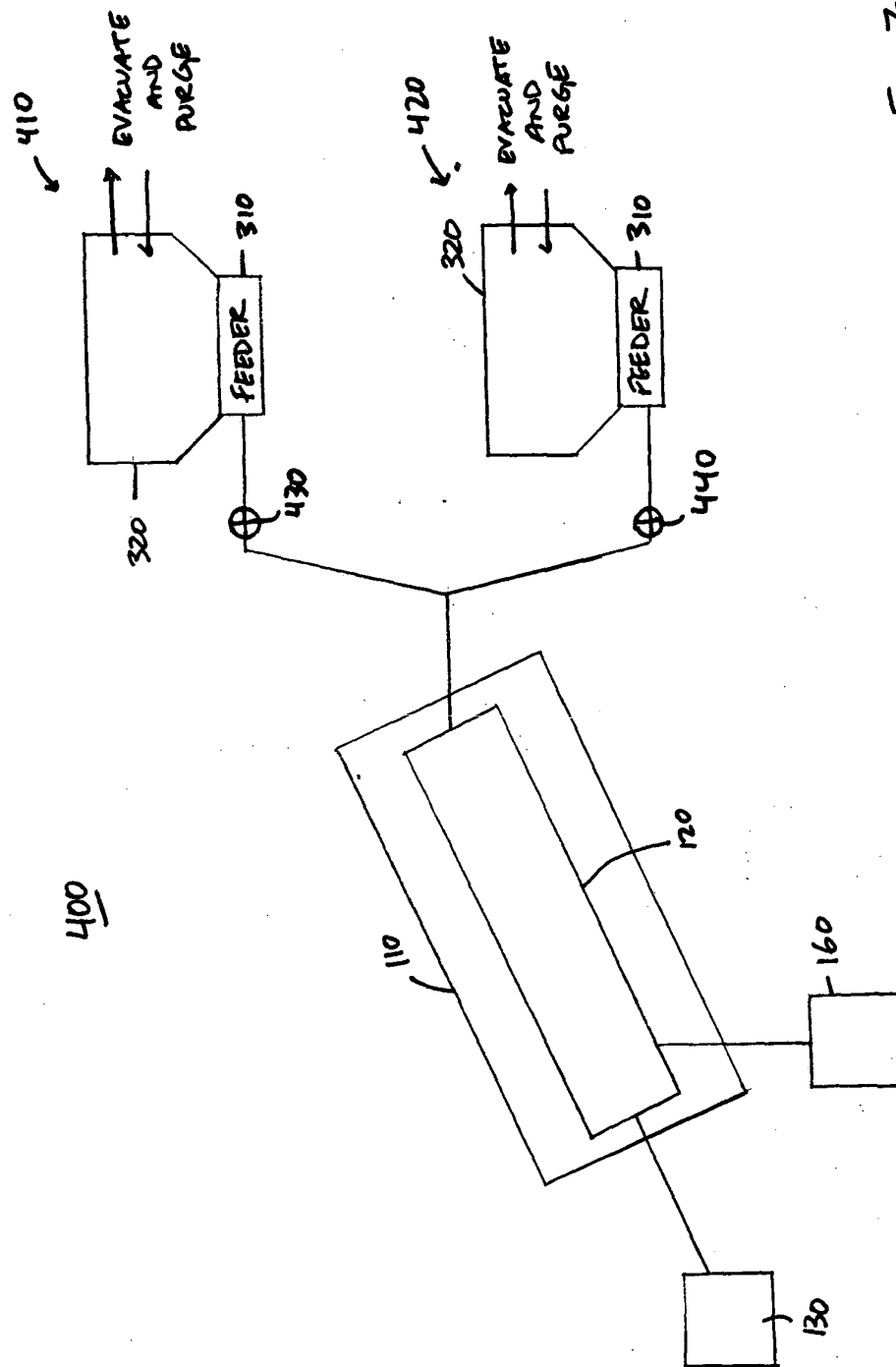


FIG 7